Sheet 1 of 2

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 65304-0161

SERIAL NO. 09/779,149

Information Disclosure Statement by Applicant APPLICANT Hajduk et al.

GROUP

(Use several sheets if necessary)

FILING DATE 02/08/2001

U.S. PATENT DOCUMENTS

Exmr Initial	Document Number	Date	Name	Class	Sub Class	Filing Date
TR	5,821,407	10/13/1998	Sekiguchi et al.	73	54.28	03/29/1996
	5,776,359	07/07/1998	Schultz et al.	252	62.51	05/08/1995
	5,764,068	06/09/1998	Katz et al.	324	727	07/25/1996
	5,728,532	03/17/1998	Ackley	435	6	05/31/1996
	5,700,953	12/23/1997	Hlady et al.	73	105	04/03/1996
	5,699,159	12/16/1997	Mason	356	351	10/29/1996
	5,626,779	05/06/1997	Okada	219	201	05/31/1994
	5,610,325	03/11/1997	Rajagopal et al.	73	54.39	06/05/1995
	5,305,633	04/26/1994	Weissenbacher et al.	73	82	12/07/1990
	5,303,030	04/12/1994	Abraham et al.	356	345	12/02/1991
	5,280,717	01/25/1994	Hoseney et al.	73	54.22	10/14/1992
	5,271,266	12/21/1993	Eschbach	73	54.33	12/06/1991
	5,236,998	08/17/1993	Lundeen et al.	525	52	06/11/1992
	5,193,383	03/16/1993	Burnham et al.	73	105	07/11/1990
	5,142,900	09/01/1992	Duke	73	54.39	10/17/1990
	5,115,669	05/26/1992	Fuller et al.	73	54.39	10/05/1990
t	5,008,081	04/16/1991	Blau et al.	422	64	10/11/1988
110	4,932,270	06/12/1990	Lurie et al.	73	862.33	03/21/1989

FOREIGN PATENT DOCUMENTS

Exmr Initial	Document Number	Date	Country	Class	Sub Class	Trans YES	lation NO
TH	WO 96/11878	4/25/1996	Schultz et al.				
		,					
							_
1							

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

To		"Micro-Indentation Relaxation Measurements in Polymer Thin Films," D.M. Shinozaki and Y. Lu, <u>J. Electronic Materials</u> , Vol. 26, No. 7, pp. 852-858, 1997.
\Box		"Ultramacroindentation Apparatus for the Mechanical Characterization of Thin Films," P.E. Wierenga and A.J.J. Franken, J. Appl. Phys., 55 (12), pp. 4244-4247, 15 June 1984.
M	-	"Microhardness Studies of Polymers and Their Transitions," F.J. Balta Calleja, <u>TRIP</u> , Vol. 2, No. 12, pp. 419-425, December 1994.

Examiner Date Considered \(\)//3

Examiner: Initial if citation considered, whether or not citation is in conformance with APEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 2 of 2

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 65304-0161

SERIAL NO.

Information Disclosure Statement by Applicant **APPLICANT** Hajduk et al. 09/779,149

(Use several sheets if necessary)

FILING DATE 02/08/2001

GROUP

U.S. PATENT DOCUMENTS

DEMAR			U.S. PATENT DUCUMENTS			
Exmr Initial	Document Number	Date	Name	Class	Sub Class	Filing Date
Th	4,893,500	01/16/1990	Fink-Jensen	73	60	09/19/1988
	4,789,236	12/06/1988	Hodor et al.	356	33	08/07/1986
	4,749,854	06/07/1988	Martens	250	225	03/05/1987
	4,740,078	04/26/1988	Daendliker et al.	356	35.5	01/14/1985
	4,680,958	07/21/1987	Ruelle et al.	73	56	07/17/1986
	4,602,501	07/29/1986	Hirata	.73	54	12/06/1984
	4,570,478	02/18/1986	Soong	73	60	04/08/1985
	4,567,774	02/04/1986	Manahan et al.	73	826	02/28/1983
	4,447,125	05/08/1984	Lazay et al.	350	96.30	04/01/1982
	4,229,979	10/28/1980	Greenwood	73	704	05/29/1979
	3,933,032	01/20/1976	Tschoegl	73	67.1	09/01/1971
	3,849,874	11/26/1974	Jeffers	29	590	11/01/1973
	3,818,751	06/25/1974	Karper et al.	73	15.6	05/23/1972
	3,805,598	04/23/1974	Corcoran	73	81	12/06/1971
XX	3,675,475	07/11/1972	Weinstein	73	89	05/25/1970

FOREIGN PATENT DOCUMENTS

Exmr Initial	Document Number	Date	Country	Class	Sub Class	Trans YES	lation NO

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

TA	"Evaluation of Young's Modulus of Polymers from Knoop Microindentation Tests," E. Amitay-Sadovsky and H.D. Wagner, <u>POLYMER</u> , Vol. 39, No. 11, pp. 2387-2390, 1998.
9	"Standard Test Method for Rubber Property – International Hardness," ASTM, D 1415-88, February 1989.
	"DMA 2980 Dynamic Mechanical Analyzer," http://www.tainst.com/dma2.html, 12/29/00.
	"Introducing the NEW DMTA V!," http://www.rheometricscientific.com/dmtaV.htm, 12/29/00
TAT	Robert H. Lacombe and Jeremy Greenblatt, "Mechanical Properties of Thin Polyimide Films," Proc. Tech. Conf. Polyimides (First) 1982, published in Polyimides: Synth., Charact., Appl., pp 647-668, 1984

Examine	er Inn	and	Date Consi

dered

Examiner: Initial if citation considered, whether or not citation is in conformance with APEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Please type a plus sign (+) inside the

PTO/SB/08A (10-96)

App. od for use through 10/31/99. OMB 0651-0031

Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

oci 1 5 2001 8 and to a collection of information unless it contains a valid OMB control number. Under the Paperwork Reduction Act of 1995,

Substitute for form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet of

Complete if Known					
Application Number	09/779,149				
Filing Date	02/08/2001				
First Named Inventor	Damian Hajduk				
Group Art Unit	2812				
Examiner Name					
Attorney Docket Number	1012-123D2	•			

				U.S. PATENT DOC	UMENTS	
Examine Initials	Cite No.1	U.S. Patent I Number	Oocument Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
11		4,699,000		Lashmore et al.	10/13/1987	
1		4,899,581		Allen et al.	02/13/1990	
L'A		5,092,179		Ferguson	03/03/1992	
OF E	\[5,437,192		Kawamoto et al.	08/01/1995	
l¥		5,438,863		Johnson	08/08/1995	
3		5,817,947		Bergerus	10/06/1998	
		5,847,283		Finot et al.	12/08/1998	
		5,877,428		Scolton	03/02/1999	
	ļ	5,892,157		Syre	04/06/1999	
		5,999,887		Giannakopoulos et al.	12/07/1999	
		6,033,913		Morozov et al.	03/07/2000	
		6,050,138		Lynch et al.	04/18/2000	
	+	6,050,139		Bousfield et al.	04/18/2000	
111	1	6,092,414		Newman	07/25/2000	

				FORI	EIGN PATENT DOCUMENT	rs		
Examiner Cite	Cite		Foreign Patent Do		Name of Patentee or	Date of Publication of	Pages, Columns, Lines, Where Relevant	
Initials*	No.1	Office ³	Number ⁴	Kind Code ⁵ (if known)	Applicant of Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear	Te
				1				
							<u></u>	
				1		•		

Examiner Signature	Im Asin	Date Considered	5/1/03	

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Uñique citation designation number. 2 See attached Kinds of U.S. Patent Documents. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 5 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

13

1012-123D2 (99-90DIV2)

Please type a plus sign (+) inside this bot

All red for use through 10/31/99. OMB 0651-0031
Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE
Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Complete if Known Substitute for form 1449A/PTO 09/779,149 **Application Number** INFORMATION DISCLOSURE Filing Date 02/08/2001 EMENT BY APPLICANT First Named Inventor Damian Hajduk Group Art Unit 2812 (use as **(Pai** sheets as necessary) **Examiner Name** Attorney Docket Number of

(Z			U.S. PATENT DOC	IMENTS	
Examiner Initials	Cite No.1 Number	Ocument Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
148	1,870,412		Kennedy	08/09/1932	7
	3,071,961		Heigl et al.	01/08/1963	e in C
	3,713,328		Aritomi	01/30/1973	8 n 2
	3,895,513		Richardson	07/22/1975	
	3,908,441		Virloget	09/30/1975	9 1 111
	4,517,830		Gunn et al.	05/21/1985	6
	4,599,219		Cooper et al.	07/08/1986	
	4,829,837		Telfer	05/16/1989	
	5,272,912		Katsuzaki	12/28/1993	2
	5,452,619		Kawanabe et al.	09/26/1995	
	5,756,883		Forbes	05/26/1998	- E
	3,798,960		Glass	03/26/1974	<u> </u>
	4,605,589		Orphanides	08/12/1986	
	4,685,328		Huebner et al.	08/11/1987	E B
	4,715,007		Fujita et al.	12/22/1987	
	4,793,174		Yau	12/27/1988	<u>م</u> ده
	4,899,575		Chu et al.	02/13/1990	2002
	4,975,320		Goldstein et al.	12/04/1990	0/2900
	5,269,190		Kramer et al.	12/14/1993	
	5,398,885		Andersson et al.	03/21/1995	8

		FOREIGN PATENT DOCUMENTS									
Exam Initial:		Cite No. ¹	Office ³	Foreign Patent Docum	nent Kind Code ⁵ (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Т6		
				JP 02297040 A		Akaha	12/1990				
	П			WO 00/17413		Symyx Technologies, Inc.	03/30/2000				
				WO 00/23921		Symyx Technologies, Inc.	04/27/2000		Ш		
	\prod			WO 00/36410			06/22/2000				
				WO 00/40331			07/13/2000	·	Ш		
				WO 00/51720		Symyx Technologies, Inc.	09/08/2000		Ш		
				WO 00/67086			11/09/2000		Ш		
				WO 96/11878		Reg. of the Univ. of California	04/25/1996				
		, and the second		WO 01/79949 A	2	Symyx Technologies, Inc.	10/25/2001		$oldsymbol{ol}}}}}}}}}}}}}}}}}}$		
1	14			WO 98/155 <u>01</u>		Symyx Technologies, Inc.	04/16/1998		لـــــــــــــــــــــــــــــــــــــ		

	Examiner Signature	Mans	pail	Date Considered
_	-			

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. 2 See attached Kinds of U.S. Patent Documents. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 5 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

PTO/SB/08A (10-96)
A ed for use through 10/31/99. OMB 0651-0031
Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449A/PTO **ORMATION DISCLOSURE** EMENT BY APPLICANT

> use as many sheets as necessary) of

Complete if Known						
Application Number	09/779,149					
Filing Date	02/08/2001					
First Named Inventor	Damian Hajduk					
Group Art Unit	2812					
Examiner Name						
Attorney Docket Number	1012-123D2 (99-90DIV2)					

	U.S. PATENT DOCUMENTS								
Examiner Initials*	Cite No.1	U.S. Patent Document Kind Code ² Number (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant				
121		5,452,614	Kato et al.	09/26/1995	Figures Appear				
		5,517,860	Lin et al.	05/21/1996	mi It				
		5,520,042	Garritano et al.	05/28/1996					
		5,532,942	Kitamura et al.	07/02/1996	ECHILOTO 14 E B 14 E C				
		5,723,972	Miyazaki	03/03/1998	<u> </u>				
		5,922,967	Motoyama	07/13/1999	TE BEST				
		5,959,297	Weinberg et al.	09/28/1999	ूं के तुष्ठ				
		5,985,356	Schultz et al.	11/16/1999	2 0 11				
		6,004,617	Schultz et al.	12/21/1999	CE P				
		6,010,616	Lewis et al.	01/04/2000					
		6,013,199	McFarland et al.	01/11/2000	E 2				
		6,030,917	Weinberg et al.	02/29/2000	23				
		6,033,913	Morozov et al.	03/07/2000	301				
		6,034,240	LaPointe	03/07/2000	<u> </u>				
		6,034,775	McFarland et al.	03/03/2000					
		6,040,193	Winkler	03/21/2000					
		6,043,317	Mumick et al.	03/28/2000					
		6,043,363	LaPointe et al.	03/28/2000					
		6,045,671	Wu et al.	04/04/2000					
		6,087,181	Cong	07/11/2000					

					FOR	EIGN PATENT DOCUMENT	'S		
Exam Initial		Cite No.1	Office	Foreign Patent Doo Number4	Kind Code ⁵ (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ₆
1	2			WO 99/18431		Symyx Technologies, Inc.	04/15/1999		
18				EP 0 317 356	A2	Kabushiki Kaisha Chichibu	05/24/1989		┼
									ᆂ
	\dashv		-						+
									工
	\dashv								+
	\neg		1						\top

	Examiner Signature	Tom Ford	Date Considered 5/1/03	
--	-----------------------	----------	------------------------	--

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. 2 See attached Kinds of U.S. Patent Documents. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

2	bo	
,	- L	

Substitute for form 1449A/PTO

INFORMATION DISCLOSURE TEMENT BY APPLICANT

JAN 5 2002 5

use as many sheets as necessary)

of |3

Complet if Known						
Application Number	09/779,149					
Filing Date	02/08/2001					
First Named Inventor	Damian Hajduk					
Group Art Unit	2812					
Examiner Name						
Attorney Docket Number	1012-123D2 (99-90DIV2)	_				

ADFINITION					
			U.S. PATENT DOC	UMENTS	ᆏ
Examiner Initials*	Cite No.1	U.S. Patent Document Kind Code (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
201		6,124,476	Guram et al.	09/26/2000	2
		6,149,882	Guan et al.	11/21/2000	<u>mi</u>
		6,151,123	Nielson	11/21/2000	<u> </u>
		6,157,449	Hajduk	12/05/2000	60
		6,175,409	Nielsen et al.	01/16/2001	<u> </u>
		6,177,528	LaPointe et al.	01/23/2001	2000 FOR
		6,182,499	McFarland et al.	02/06/2001	₹ <u></u>
		6,187,164	Warren et al.	02/13/2001	2 7 1
		6,203,726	Danielson et al.	03/20/2001	08 C
		6,225,487	Guram	05/01/2001	
		6,225,550	Hornbostel et al.	05/01/2001	B MED
		6,242,623	Boussie et al.	06/05/2001	
		6,248,540	Weinberg et al.	06/19/2001	2
		6,260,407	Petro et al.	07/17/2001	280
		6,265,226	Petro et al.	07/24/2001	
		6,265,601	Guram et al.	07/24/2001	X
		6,268,513	Guram et al.	07/31/2001	
		6,294,388	Petro	09/25/2001	
		6,296,771	Miroslav	10/02/2001	
20	1	5.481.153	Turner	01/02/1996	

				FORE	IGN PATENT DOCUMENT	rs		
	C:4-	F	oreign Patent Do	cument	Name of Patentee or	Date of Publication of	Pages, Columns, Lines, Where Relevant	I
Examiner Initials*	Cite No. ¹	Office ³	Number ⁴	Kind Code ⁵ (if known)	Applicant of Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear	T6
								<u> </u>
								$oldsymbol{ol}}}}}}}}}}}}}}}}}$
								_

Examiner	7		Date	
Signature	Me	Deur	Considered	5/40>

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

Please	type	a plus	sign	(+)	inside	this	ь
--------	------	--------	------	-----	--------	------	---

PTO/SB/08A (10-96)

Under the Paperwork Reduction Act of 1995, no persons are required to re

A) ed for use through 10/31/99. OMB 0651-0031	
Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE	
espond to a collection of information unless it contains a valid OMB control number.	

Substitute for form 1449A/PTO

INFORMATION DISCLOSURE Statement by applicant

(use as many sheets as necessary)

of

С	mplete if Known	1
Application Number	09/779,149	
Filing Date	02/08/2001	
First Named Inventor	Damian Hajduk	
Group Art Unit	2812	
Examiner Name		
Attorney Docket Number	1012-123D2 (99-90DIV2)	

	SZ						
DEMARKE				U.S. PATENT DOC	UMENTS		
Examiner Initials*	Cite No.1	Number	Kind Code ²	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
TAN		6,306,658 E	31	Turner et al.	10/23/2001		
		6,315,923 E	31	Devenney et al.	11/13/2001	C	
		6,326,090 E	31	Schultz et al.	12/04/2001	2	
		6,336,353 E	32	Matsiev et al.	01/08/2002	<u> </u>	
111	7	5,051,239		von der Goltz	09/24/1991		
						- <u>6</u>	2
					•		
						39	غ
							5_
						- F	
						<u> </u>	
						FEB	<u> </u>
ļ						0 8	4
						5	
		ļ				C P 1	4
						7 E	\Box
 							
			-		_	2800	
}							
11 I		I			<u> </u>		

			·	FORE	EIGN PATENT DOCUMENT	rs		
Examiner	Cite		Foreign Patent Do		Name of Patentee or	Date of Publication of	Pages, Columns, Lines, Where Relevant	\Box
	No.1	Office ³	Number ⁴	Kind Code ⁵ (if known)	Applicant of Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear	T6
								$\perp \perp \downarrow$
								\perp
								$\perp \perp \downarrow$
								oxdot
								$oldsymbol{\perp}$
L		li						السلا

Examiner		Date	0/10
Signature	1 miles	Considered	3/1/03

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

Please type a plus sign (+) inside this	Please	type a	plus	sign (+)) inside	this
---	--------	--------	------	----------	----------	------

]	HAI	ว	5	2002
	1 / 10	•	. 1	7000

PTO/SB/08B (10-96)
Applied for use through 10/31/99. OMB 0651-0031
Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE
Under the Paperwork Reduction Act of 1995, no persons are required to despond to a collection of information unless it contains a valid OMB control number.

Substitu	ute for form 1449B/PTO	TRADEMARK	Co	emplete if Known
			Application Number	09/779,149
INF	ORMATION	DISCLOSURE	Filing Date	02/08/2001
STA	TEMENT F	BY APPLICANT	First Named Inventor	Damian Hajduk
017	VI EIVIEIVI E	AI LIOAN	Group Art Unit	2812
	(use as many st	neets as necessary)	Examiner Name	
Sheet	1	of 0	Attorney Docket Number	1012-123D2 (99-90DIV2)

	OTHER PRIOR ART NON PATENT LITERA	TURE DOCUME	NTS	
Examiner Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the artic item (book, magazine, journal, serial, symposium, catalog, etc.), date, publisher, city and/or country where publ	page(s), volume-iss	e), title of the sue number(s),	T²
M	U.S. Patent Application Serial No. 09/939,404 entitled "Higand Bulge Testing of Material Libraries," (D. Hajduk et al.)	gh Throughput filed on Augus	Mechanical Property st 24, 2001.	
	U.S. Patent Application Serial No. 09/939,252 entitled "F Serial Property Testing of Material Libraries," (P. Mansk			
	U.S. Patent Application Serial No. 09/939,139 entitled Screening," (M. Kossuth et al.) filed on August 24, 200		hput Fabric Handle	
	U.S. Patent Application Serial No. 09/939,149 entitled Testing Of Materials" (Paul Manksy et al.) filed on Aug		hput Rheological	
	U.S. Patent Application Serial No. 09/939,263 entitled "Hig Testing of Materials Libraries Using Capacitance," (D. Haje			
	U.S. Patent Application Serial No. 09/938,994 entitled "Hig Testing of Materials Libraries Using a Piezoelectric," (D. H			
	The family of applications for U.S. Patent Application Se Design of Combinatorial Material Libraries" (Lacy, et al.			
	U.S. Application Serial No. 09/578,997 entitled "High" Method of Using Same" filed May 25, 2000	Γhroughput Vi	iscometer and	
	ODIAN, Principles of Polymerization, 3rd Ed., John W	iley & Sons, l	Inc. (1991)	
	TIMOSHENKO, S., Theory of Plates and Shells, McGi	aw-Hill, New	York #940	-
rate	European Search Report dated December 10, 2001		RECEIVE FEB - 6 201 10LOGY CENT	•
			₩ २ ∪	
Examiner Signature	Im Jung	Date Considered	280 /1/07	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not

considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² Applicant is to place a check mark here if English language Translation is attached.

PTO/SB/08B (10-96)
Applied for use through 10/31/99. OMB 0651-0031
Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE Under the Paperwork Reduction Act of 1995, no person sare required to respond to a collection of information unless it contains a valid OMB control number.

Subs	titute for form 1449B/PT		TRADEMARY	Co	mplete if Known	
				Application Number	09/779,149	$\exists \Box$
INF	FORMATION	1 C	DISCLOSURE	Filing Date	02/08/2001	$\overline{\mathbb{C}}$
ST	ATEMENT	RY	APPLICANT	First Named Inventor	Damian Hajduk	
0,	AILMENI		All LIO/All	Group Art Unit	2812	ž
	(use as many	shee	ts as necessary)	Examiner Name		ᅼᆜ
Sheet	1	of	0	Attorney Docket Number	1012-123D2 (99-90DIV2)	
						20

			\circ
		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	\approx
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	\$
TAR		U.S. Application Serial No. 09/420,334 entitled "Graphic Design of Combinatorial Material Libraries" (Lacy, et al.) filed on October 18, 1999	
		U.S. Patent Application Serial No. 09/305,830 titled "Synthesizing Combinatorial Libraries of Materials" (Rust, et al.) filed on May 5, 1999	
		U.S. Application Serial No. 09/550,549 entitled "Automated Process Control And Data Management System And Methods" (Crevier, et al.) filed on April 14, 2000	
		U.S. Application Serial No. 09/755,623 entitled "Laboratory Database System and Methods For Combinatorial Materials Research" (Dorsett, Jr., et al.) filed on January 5, 2001.	
		The family of applications for U.S. Application Serial No. 09/227,558 entitled, "Apparatus and Method of Research for Creating and Testing Novel Catalysts, Reactions and Polymers" (Turner et al.) filed January 8, 1999	
		U.S. Application Serial No. 09/235,368 entitled "Polymerization Method From the Combinatorial Synthesis and Analysis of Organometallic Compounds and Catalysts" (Weinberg et al.) filed on January 21, 1999	;
		U.S. Provisional Application Serial No. 60/122,704 entitled "Controlled, Stable Free Radica Emulsion and Water-Based Polymerizations" (Klaerner et al.) filed on March 9, 1999	1
		The family of applications for U.S. Application Serial No. 09/156,827 entitled "Formation of Combinatorial Arrays of Materials Using Solution-Based Methodologies" (Giaquinta et al.) filed September 18, 1998	
		The family of applications for U.S. Application Serial No. 09/567,598 entitled "Polymer Libraries on a Substrate, Method for Forming Polymer Libraries on a Substrate and Characterization Methods with Same" (Boussie et al.) filed May 10, 2000	
THE)	U.S. Application Serial No. 09/579,338 entitled "Rheo-Optical Indexer and Method of Screening and Characterizing Arrays of Materials" (Carlson et al.) filed on Materials (Carlson et al.)	
		TEB - 6 2007 LOGY CENTE	TCF WE

1	Examiner Signature	Nows And	Date Considered

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Assistant Commissioner for Patents, Washington, DC 20231.

¹ Unique citation designation number. ² Applicant is to place a check mark here if English language Translation is attached.

Please	type	а	plus	sign	(+)	inside	this	b
--------	------	---	------	------	-----	--------	------	---

1			7. 7
_			1
1.	JAN	2 -	** 81
Τ_	416	4 3	2002 5

PTO/SB/08B (10-96)
Appered for use through 10/31/99. OMB 0651-0031
Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

	tute for form 1449B/PTC	178	Л	on unless it contains a valid OMB control number complete if Known	
			Application Number	09/779,149	
INF	ORMATION	I DISCLOSURE	Filing Date	02/08/2001	
STA	ATEMENT I	BY APPLICANT	First Named Inventor	Damian A. Hajduk	
"	~ · C · · · · ·	BI AII EIGAII	Group Art Unit	2812	
	(use as many s	sheets as necessary)	Examiner Name		
Sheet	1	of 0	Attorney Docket Number	1012-123D2 (99-90DIV2)	

		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²				
TH		Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. DWLT, C., "A Simple Capillary Viscometer" Physics Education, March 1975, vol. 10, e. 2, pp. 102-103 DUNG, W.C., Roark's Formulas for Stress and Stain, 1989 LI, S.I. and Shahida Begum, "Fabric Softeners and Softness Perception", Ergonomics, 37, No. 5, pp. 801-806 (1994). STERBERG, Peter M. and Stephen D. Senturia, "M-TEST: A Test Chip for MEMS Material operty Measurement Using Electrostatically Actuated Test Structures," Journal of coroelectromechanical Systmes, Vol. 6, No. 2, June 1997 M. J.O. and B. Lewis Slaten, "Objective Assessment of Fabric Handle in Fabrics Treated With ame Retardants," Journal of Testing and Evaluation, JTEVA, Vol. 24, No. 4, July 1996, pp. 3-228. AEEL, MASTURA and Jiang Liu, "An Empirical Model for Fabric Hand" Textile esearch Journal 62, 1, pp. 31-38 (1991). N.N. NING and K.C. Yen, "Physical Interpretations of Curves Obtained Through the Fabric traction Process for Handle Measurement," Textile Research Journal 62(5), pp. 279-290 (1992). Innale-O-Meter", Thwing-Albert Instrument Company, Philadelphia, PA. ROVER, G. et al., "A Screening Technique for Fabric Handle", J. Text. Inst., 1993, 84 (1), J. Textile Institute, pp. 486-494.					
		YOUNG, W.C., Roark's Formulas for Stress and Stain, 1989					
ALI, S.I. and Shahida Begum, "Fabric Softeners and Softness Perception", Ergonomics, v.37, No. 5, pp. 801-806 (1994). OSTERBERG, Peter M. and Stephen D. Senturia, "M-TEST: A Test Chip for MEMS Material Property Measurement Using Electrostatically Actuated Test Structures," Journal of							
		RAEEL, MASTURA and Jiang Liu, "An Empirical Model for Fabric Hand" Textile Research Journal 62, 1, pp. 31-38 (1991).					
		PAN, NING and K.C. Yen, "Physical Interpretations of Curves Obtained Through the Fabric Extraction Process for Handle Measurement," Textile Research Journal 62(5), pp. 279-290 (1992).					
		"Handle-O-Meter", Thwing-Albert Instrument Company, Philadelphia, PA.					
GROVER, G. et al., "A Screening Technique for Fabric Handle", J. Text. Inst.,							
	:	FEB-6 TECHNOLOGY C					
		FEB-6 2002 ECHNOLOGY CENTER 2800					
Examine Signature		Im pour Date Considered 5/1/07					

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² Applicant is to place a check mark here if English language Translation is attached.